



APPROVAL SHEET

Approval Specification	Customer's Approval Certificate
TO: Part No.: Customer's Part No.:	Please return this copy as a certification of your approval Checked & Approved by: Date:

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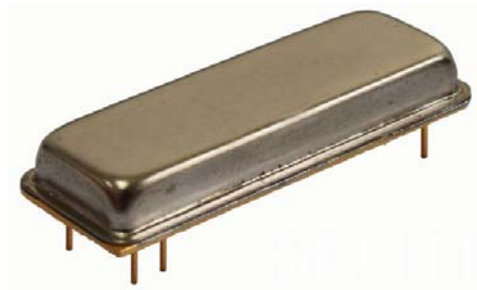


Part No.	:	SF1569
Pages	:	6
Date	:	2015/10/30
Revision	:	1.0

Prepared by:	梁浩
Checked by:	
Approved by:	

Application

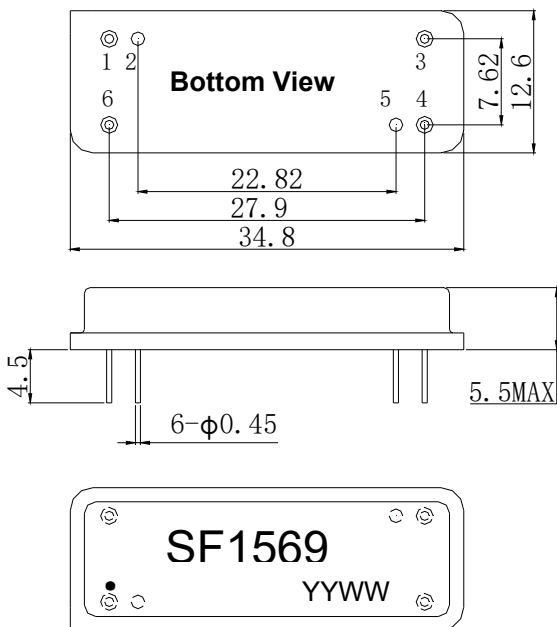
- High-loss SAW component
- Low amplitude ripple
- Sharp rejections at both out-bands
- Passband 15 MHz
- Low Shape factor



Features

- RoHS compatible
- Package size 34.8x12.6x5.50mm³
- Package Code DIP3512
- Electrostatic Sensitive Device(ESD)

Package Dimensions (Unit: mm)



Pin Configuration

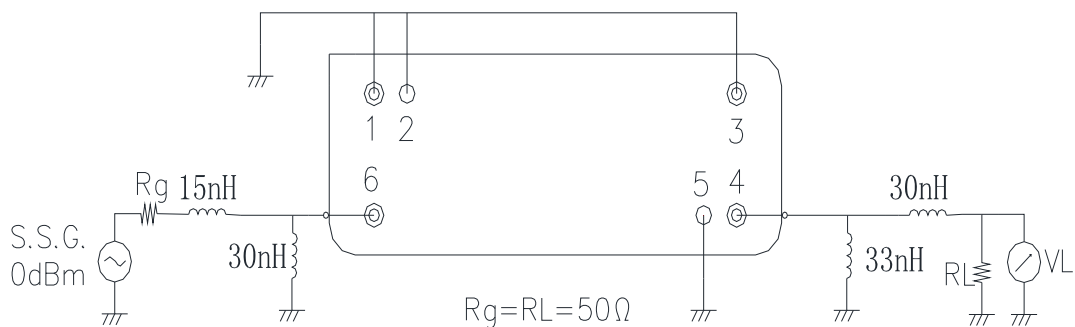
Pin No.	Description
6	Input
4	Output
1,2,3,5	Ground

Marking Description

S	Trademark
F	SAW Filter
1569	Part Number
●	Pin 1
YYWW	Year Code & Week Code

*Fig: If the products produced in 06th week of 2012, The year code & week code is 1206.

Test Circuit(Bottom View)



Performance**Maximum Rating**

Item		Value	Unit
DC Voltage	V _{DC}	3	V
Operation Temperature	T	-40 ~ +85	°C
Storage Temperature	T _{stg}	-55 ~ +125	°C
RF Power Dissipation	P	10	dBm

Electronic Characteristics

Test Temperature: 25°C ± 2°C

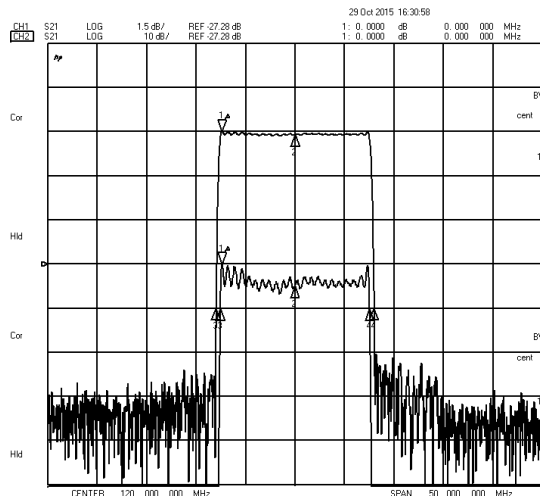
Terminating source impedance: 50Ω

Terminating load impedance: 50Ω

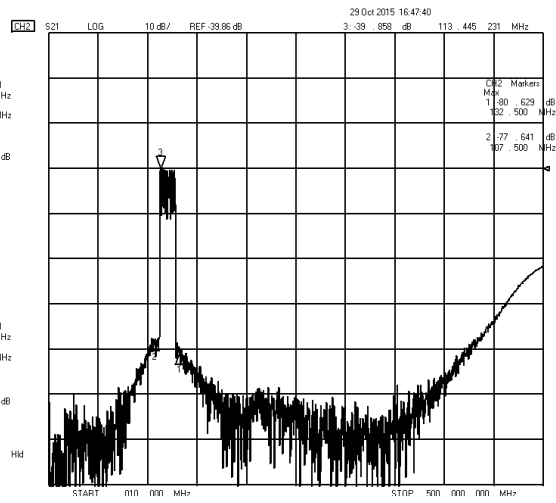
Item		Minimum	Typical	Maximum	Unit
Center Frequency	f _c	119.85	120.00	120.15	MHz
Insertion Loss(min)	IL		27.30	32.00	dB
Amplitude Ripple	Δα		1.00	1.50	dB
1.5dB Bandwidth	BW _{1.5dB}	15.00	15.09		MHz
3dB Bandwidth	BW _{3dB}		15.19		MHz
20dB Bandwidth	BW _{20dB}		15.70	15.8	MHz
40 dB Bandwidth	BW _{40dB}		15.97		MHz
Absolute Delay@F0	GDR		3.87	4.0	us
Absolute Attenuation	α				
	107.50MHz	50.0	52.0		dB
	132.50MHz	50.0	52.0		dB

Frequency Characteristics

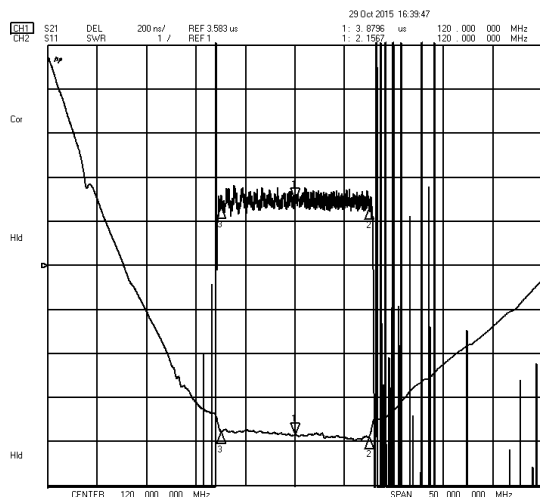
Frequency Response



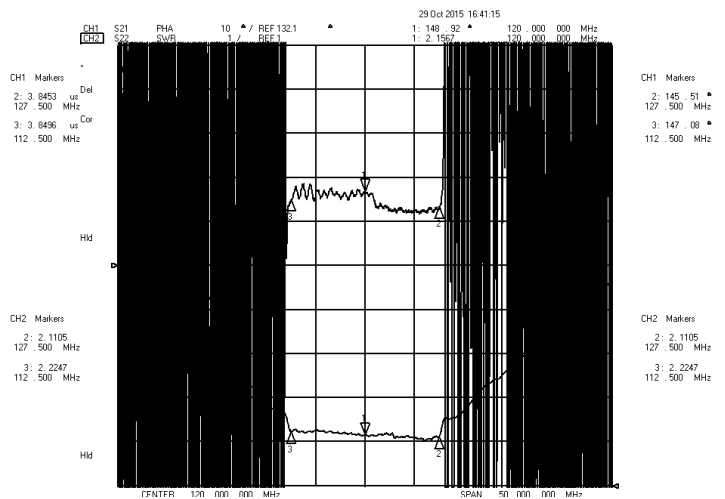
Frequency Response (wideband)



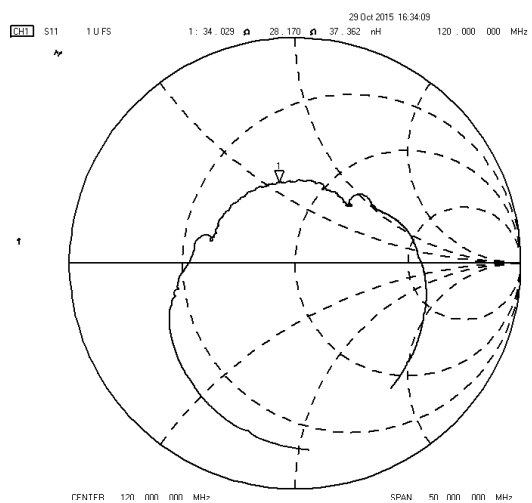
Delay Ripple & S11 VSWR



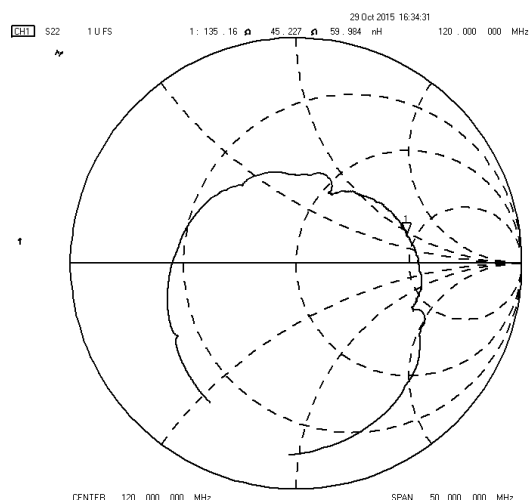
Phase Linearity & S22 VSWR



S11 Smith Chart

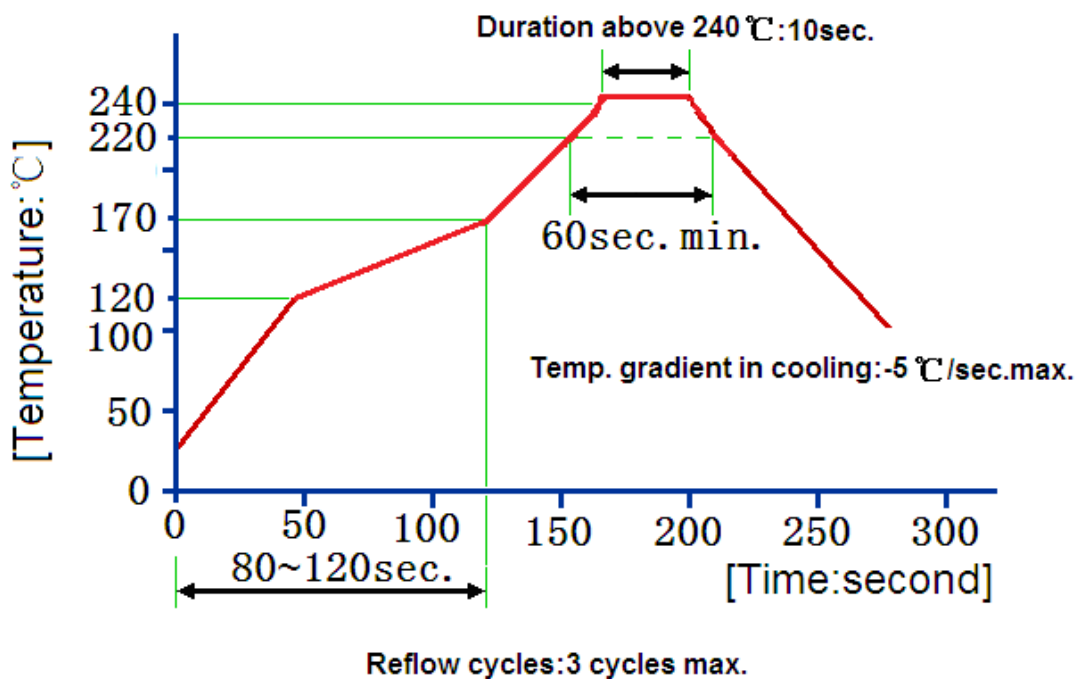


S22 Smith Chart



Reliability (The SAW components shall remain electrical performance after tests)

No.	Test item	Test condition
1	Temperature Storage	(1) Temperature: $85^{\circ}\text{C}\pm 2^{\circ}\text{C}$, Duration: 250h, Recovery time: $2\text{h}\pm 0.5\text{h}$ (2) Temperature: $-55^{\circ}\text{C}\pm 3^{\circ}\text{C}$, Duration: 250h, Recovery time: $2\text{h}\pm 0.5\text{h}$
2	Humidity Test	Conditions: $60^{\circ}\text{C}\pm 2^{\circ}\text{C}$, 90~95% RH Duration: 250h
3	Thermal Shock	Heat cycle conditions: $T_A=-55^{\circ}\text{C}\pm 3^{\circ}\text{C}$, $T_B=85^{\circ}\text{C}\pm 2^{\circ}\text{C}$, $t_1=t_2=30\text{min}$, Switch time: $\leq 3\text{min}$, Cycle time: 100 times, Recovery time: $2\text{h}\pm 0.5\text{h}$.
4	Vibration Fatigue	Frequency of vibration: 10~55Hz Amplitude: 1.5mm Directions: X,Y and Z Duration: 2h
5	Drop Test	Cycle time: 10 times Height: 1.0m
6	Solder Ability Test	Temperature: $245^{\circ}\text{C}\pm 5^{\circ}\text{C}$ Duration: 3.0s--5.0s Depth: DIP--2/3, SMD--1/5
7	Resistance to Soldering Heat	(1) Thickness of PCB: 1mm, Solder condition: $260^{\circ}\text{C}\pm 5^{\circ}\text{C}$, Duration: $10\pm 1\text{s}$ (2) Temperature of Soldering Iron: $350^{\circ}\text{C}\pm 10^{\circ}\text{C}$, Duration: 3~4s, Recovery time : $2 \pm 0.5\text{h}$

Recommended Reflow Soldering Diagram

Notes

1. As a result of the particularity of inner structure of SAW products, it easy to be breakdown by electrostatic, so we should pay attention to **ESD protect** in the test.
2. **Static voltage** between signal load and ground may cause deterioration and destruction of the component. Please avoid static voltage.
3. **Ultrasonic cleaning** may cause deterioration and destruction of the component. Please avoid ultrasonic cleaning.
4. Only leads of component may **be soldered**. Please avoid soldering another part of component.
5. There is a close relationship between the device's performance and **matching network**. The specifications of this device are based on the test circuit shown above. L and C values may change depending on board layout. Values shown are intended as a guide only.